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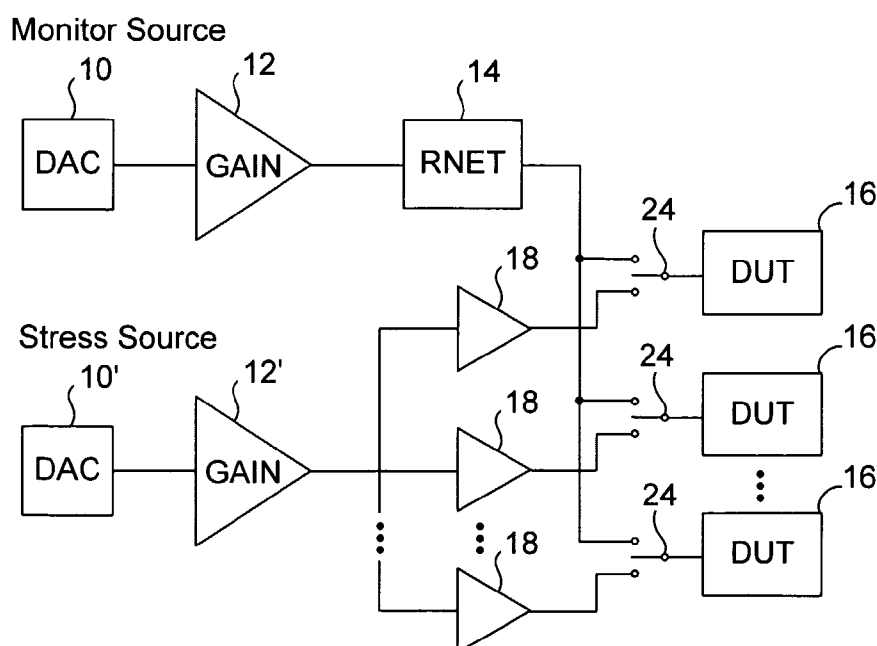
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(54) Title: DUAL CHANNEL SOURCE MEASUREMENT UNIT FOR SEMICONDUCTOR DEVICE TESTING



(57) Abstract: A dual channel source measurement unit for reliability testing of electrical devices provides a voltage stress stimulus to a device under test and monitors degradation to the device under test caused by the stress simulator. The dual channel source measurement unit decouples the stress and monitor portions of the unit so that the requirements of each can be optimized. Deglitching and current clamp switches can be incorporated in the dual channel source measurement unit to prevent glitches in the switching circuitry and to limit or clamp current flow to or from the monitor and stress sources.

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